How to make tomography practical: several FEI use cases
Remco Schoenmakers, FEI Netherlands

In this presentation we present various uses of tomography by FEI customers. In particular we will discuss how we bridge the gap between mathematical theory and a practical, user-friendly implementation and deal with issues as alignment, low S/N, fast reconstruction speeds and a clear workflow. We will discuss in more detail on the combination of multi-modal acquisitions, reconstructions and image fusion techniques in a project around 3D imaging for semi-conductor industry called AMTIC: Automated Multi-modal Tomography for sub 22nm IC devices. This project is conducted by the CWI in Amsterdam and the Quantitative Imaging Group of the Technical University in Delft (both the Netherlands) as academic partners for algorithm development, and FEI and IMEC (Belgium) as industrial partners for commercialization of the results.